

The Scorpion BRiZ Test & Programming station is a compact, totally customizable, all-in-one test station.

It can be configured to perform in-circuit, functional & boundary testing, and in-system programming. So, in one manufacturing stage you can achieve the highest level of test coverage, perform device programming, and meet & exceed your throughput requirements.

This makes BRiZ a truly affordable tester that you cannot afford to be without.

In-System Programming

Boundary Scan Test

Functional Test

In-Circuit Test

The BRiZ is designed to be configurable with a variety of off the shelf test instrumentation for performing functional test:

VXI, PXI, and GPIB based instrumentation for analog & digital functional test

LabWindows CVI™, Labview™, Visual C/C++, etc.

Test Capability

Ensure the highest level of test coverage by using a combination of boundary scan, in-circuit and functional test techniques.

The Briz is powered by Acculogic's powerful & patented boundary scan system. This allows fast programming of on board devices using JTAG/boundary scan ports. In addition, the BRiZ is equipped with an auxiliary, ultra-fast, universal In-System Programmer, which enables device programming for devices that are not JTAG/1149.x compliant. The built in multiplexer permits programming multiple devices in parallel.



Quick Changeover, Mechanical Test Fixture

Equipped with a quick changeover, mechanical test fixture the need for a vacuum pump is eliminated. This allows the BRiZ to be quickly and easily deployed at various locations across the production floor.

- Up to 1,024 non-multiplexed tester channels
- Integrated device programmer, with support for over 3,000 device models, allows parallel programming of up to 8 targets
- Supports industry standard vector formats SVF, JAM/STAPL, IEEE 1532
- Multiple Boundary Scan/JTAG digital I/O

Specifications:

General System Specifications

System Dimensions

(monitor arm not included)
9" Server Cabinet - 16U high - 23.6"(width) x 32"(depth) x 34.25"(height)

Power Requirement

100 - 240 VAC, Single phase
Full load current: 15A

Computer

Intel CORE 2.9G 6M 1150P 4 CORE I5-4570S
8G DDR3-1600 RAM
1T Hard drive-
Windows Operating System

In-Circuit Test Specifications

Number of pins

In stages from 64 pins to max. 1,024 pins

Stimuli

Two stimuli from 10 mV, 2.44 nA to 10 V, 1 A one 100 V, 20 mA stimulus

Matrix (Relay matrix)

Real four-wire relay matrix, for four-wire measurement, combination of any test points possible

Guarding

Active guarding on each test point up to 1 A, with programmable current limit

Standard measuring ranges:

Resistance (R)	1 Ω to 360 M Ω
Inductivity (L)	10 μ H to 10 H
Capacity (C)	10 pF to 10 F

Optional test procedure

ChipScan

For detecting opens and shorts in IC's

Boundary Scan Specifications

Up to 4 JTAG ports
Programmable logic
In-system programming
Digital I/O
Supports all industry standards: IEEE 1149.1, IEEE 1149.6, IEEE 1532, etc.

Power Supply

Up to 4 programmable power supplies
0 – 60 V

In-System Programming Specifications

Gang programming of up to 8 targets
Device library of over 3,000 and growing